# **Power MOSFET**

# 60 V, 6.5 m $\Omega$ , 70 A, Single N-Channel

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parar	Symbol	Value	Unit		
Drain-to-Source Voltage			V <sub>DSS</sub>	60	V
Gate-to-Source Voltage	Э		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	70	Α
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)	Steady	T <sub>C</sub> = 100°C		49	
Power Dissipation	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	63	W
R <sub>θJC</sub> (Notes 1, 2, 3)		T <sub>C</sub> = 100°C	1	31	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	16	Α
Current R <sub>θJA</sub> (Notes 1 & 3, 4)	Steady	T <sub>A</sub> = 100°C		11	
Power Dissipation	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.2	W
R <sub>θJA</sub> (Notes 1, 3)		T <sub>A</sub> = 100°C	1	1.6	
Pulsed Drain Current	ulsed Drain Current $T_A = 25^{\circ}C$ , $t_p = 10 \mu s$			440	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	68	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 3.6 A)			E <sub>AS</sub>	166	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{ heta JC}$	2.4	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	47	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51–12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

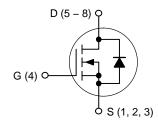


## ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX	
60 V	6.5 mΩ @ 10 V	70 A	
	9.1 mΩ @ 4.5 V	708	

#### N-Channel





# WDFN8 (μ8FL) CASE 511AB



670L = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
Pb-Free Package

(Note: Microdot may be in either location)

### ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS	•			•	•		•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				27		mV/°C	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$	T <sub>J</sub> = 25°C			10		
		V <sub>DS</sub> = 60 V	T <sub>J</sub> = 125°C			250	μΑ	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA	
ON CHARACTERISTICS (Note 5)					-			
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.2		2.0	V	
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-4.7		mV/°C	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 35 A		5.4	6.5	+	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 35 A		7.3	9.1	mΩ	
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>I</sub>	<sub>D</sub> = 35 A		82		S	
CHARGES AND CAPACITANCES	•			•			•	
Input Capacitance	C <sub>ISS</sub>				1400			
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 M⊢	Iz, V <sub>DS</sub> = 25 V		690		pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>				15		1	
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 35 A			9.0		nC	
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 35 A			20		nC	
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V}; I_D = 35 \text{ A}$			2.5		nC	
Gate-to-Source Charge	Q <sub>GS</sub>				4.5			
Gate-to-Drain Charge	$Q_{GD}$				2.0			
Plateau Voltage	$V_{GP}$				3.1		V	
SWITCHING CHARACTERISTICS (Note 6	)			•	•		•	
Turn-On Delay Time	t <sub>d(ON)</sub>				11			
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{D}$	ne = 30 V.		60		1	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 35 \text{ A}, R_G = 2.5 \Omega$			15		ns	
Fall Time	t <sub>f</sub>				4			
DRAIN-SOURCE DIODE CHARACTERIS	TICS			ı				
Forward Diode Voltage	ge V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.9	1.2		
		$I_{S} = 35 \text{ A}$ $T_{J} = 125^{\circ}\text{C}$		0.8		V		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/d_{t} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 35 \text{ A}$			34			
Charge Time	t <sub>a</sub>				17		ns	
Discharge Time	t <sub>b</sub>				17		1	
Reverse Recovery Charge	Q <sub>RR</sub>				19		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

6. Switching characteristics are independent of operating junction temperatures.

#### TYPICAL CHARACTERISTICS

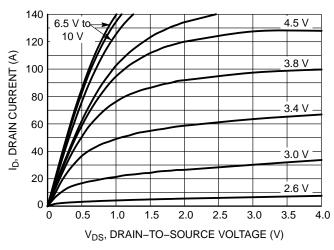


Figure 1. On-Region Characteristics

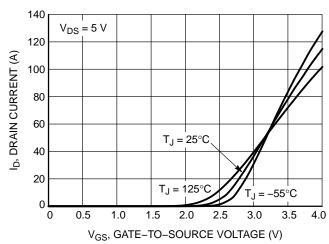


Figure 2. Transfer Characteristics

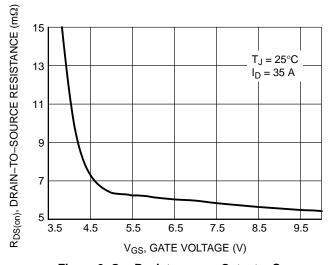


Figure 3. On–Resistance vs. Gate–to–Source Voltage

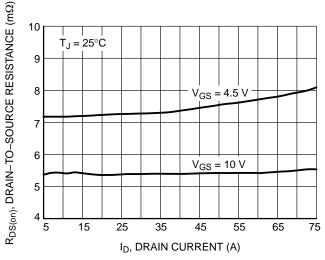


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

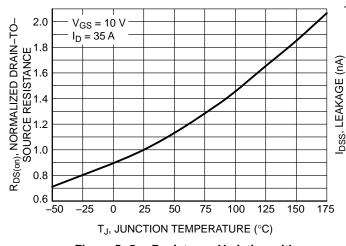


Figure 5. On–Resistance Variation with Temperature

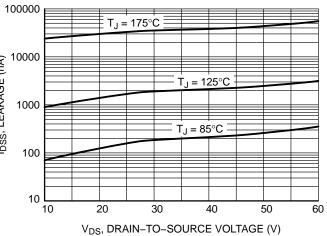


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

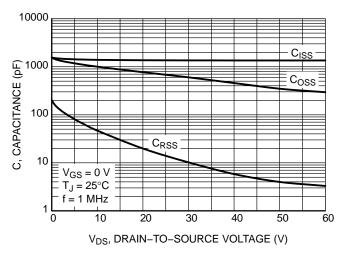


Figure 7. Capacitance Variation

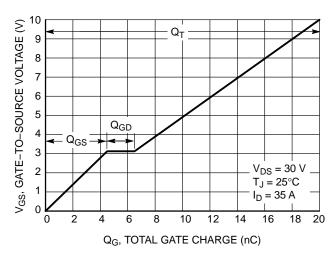


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

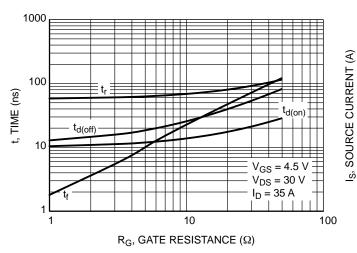


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

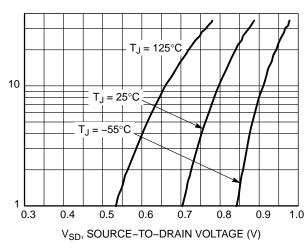


Figure 10. Diode Forward Voltage vs. Current

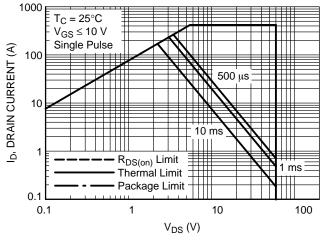


Figure 11. Maximum Rated Forward Biased Safe Operating Area

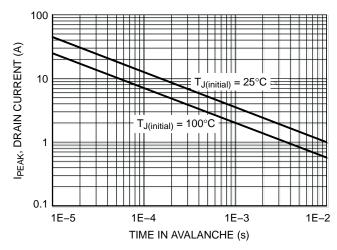


Figure 12. Maximum Drain Current vs. Time in Avalanche

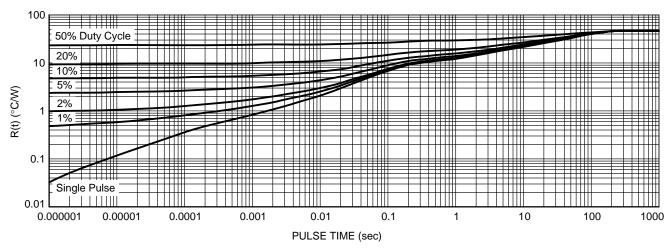


Figure 13. Thermal Characteristics

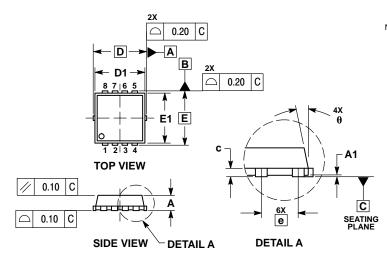
#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTTFS5C670NLTAG	670L	WDFN8 (Pb–Free)	1500 / Tape & Reel
NTTFS5C670NLTWG	670L	WDFN8 (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

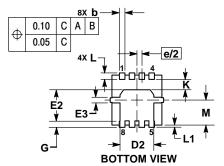
#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

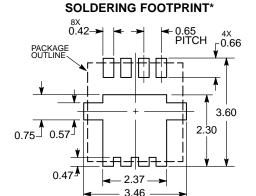


#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
   CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	





DIMENSION: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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